Abstracts

Probe Tip Invasiveness at Indirect Electro-Optic Sampling of MMIC

W. Mertin, C. Roths, F. Taenzler and E. Kubalek. "Probe Tip Invasiveness at Indirect Electro-Optic Sampling of MMIC." 1993 MTT-S International Microwave Symposium Digest 93.3 (1993 Vol. III [MWSYM]): 1351-1354.

For the first time, a systematic experimental investigation up to 40 GHz of the invasiveness of an electro-optic probe tip at indirect electro-optic sampling of MMICs is made. The direct electro-optic sampling technique is used to measure the influence on the transmission characteristic of a coplanar waveguide. As far as possible the results are compared with network analyzer measurements.

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